Special Issue

Machine Learning Methods for Solving Optical Imaging Problems

Message from the Guest Editors

Over the recent years, consistent efforts have been put into applying machine learning methods to address various problems in optical imaging. Across a growing number of optical imaging techniques, machine learning shows better performance over conventional methods. This Special Issue aims to highlight the potentials of machine learning methods across a spectrum of optical imaging techniques, including optical coherence tomography, photoacoustic imaging, optical spectroscopy, super-resolution microscopy and polarization imaging. Additionally, the objective is to investigate potential improvements of deep learning methods by leveraging prior knowledge of optical imaging systems, also known as physics-informed deep learning. Lastly, it aims to explore other emerging deep learning frameworks from the broader academic community, such as vision transformer, to provide additional solutions for optical imaging problems. In this Special Issue, original research articles and reviews are welcome. We look forward to receiving your contributions.

Guest Editors

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Deadline for manuscript submissions

closed (15 November 2024)

Electronics

About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

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